

Enhancement Mode P-Channel Power MOSFET

PDFN5X6/PMOS/-30V/ \pm 20V/-1.5V/-40A/7.6m Ω

Rev_{0.5}





-30V, 7.6mΩ, -40A, P-Channel Enhancement MOSFET

1.Features

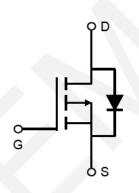
- ◆ -30V MOSFET technology
- ◆ Low on-state resistance
- Fast switching
- ♦ Vgs±20V
- ◆ 100% RG Tested
- ◆ 100% UIS Tested

2.Ap	pli	icat	ions
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- Power Switching Application
- ◆ Load Switching



V _{DS}	R _{DS(on)} Typ.	I _D Max.
00)/	7.6mΩ @ -10V	40.4
-30V	10.4mΩ @ -4.5V	-40A



Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WX080P03PA	080P03	PDFN5X6	5,000	50,000

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	$V_{ extsf{DSS}}$	-30	V
Gate to Source Voltage	V_{GSS}	±20	V
Drain Current (DC)	I _D	-40	А
Drain Current (Pulse), PW≤300μs	I _{DP}	-160	А
Total Dissipation	P_{D}	52	W
Avalanche Energy, Single Pulsed	E _{AS}	138	mJ
Junction Temperature	T _j	150	°C
Storage Temperature	T _{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5. Thermal Resistance Ratings (Note 2)

Parameter	Symbol	Value	Unit
Junction to Case	$R_{ heta JC}$	2.4	°C/W

Note 2: When mounted on 1 inch square copper board $t \le 10$ sec The value in any given application depends on the user's specific board design.

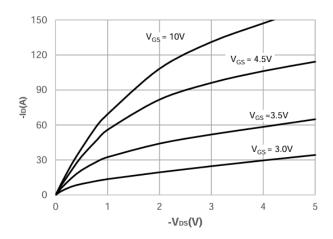
6.Electrical Characteristics at Ta=25°C (Note 3)

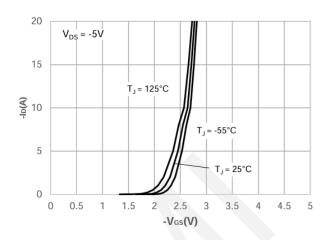
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = 250 \mu A, V_{GS} = 0 V$	-30	-	-	V
Zero-Gate Voltage Drain Current	I _{DSS}	V_{DS} =-30V, V_{GS} = 0V	-	-	1	μA
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0V$	ı	-	±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_{DS}=250\mu A$	-1.3	-1.5	-2.3	V
Static Drain to Source On-State	Б	I _D =-12A, V _{GS} = -10V		7.6	9.5	mΩ
Resistance	R _{DS(on)}	$I_D = -8A$, $V_{GS} = -4.5V$	-	10.4	15	mΩ
Input Capacitance	C _{iss}	V _{GS} =0V,	-	2278	-	pF
Output Capacitance	C _{oss}	V _{DS} =-15V,	-	322	-	pF
Reverse Transfer Capacitance	C _{rss}	Frequency=1.0MHz	1	254	-	pF
Turn-ON Delay Time	t _{d(on)}		ı	6	-	ns
Rise Time	t _r	$V_{DD} = -15V$ $V_{GS} = -10V, I_{D} = -10A,$	-	2	-	ns
Turn-OFF Delay Time	$t_{d(off)}$	$V_{GS} = -10V$, $I_D = -10A$, $R_{GEN} = 3\Omega$	-	90	-	ns
Fall Time	t _f		-	52	-	ns
	Q_g	V_{DS} =-15V, V_{GS} = 0 to -10V,	-	41	-	nC
Total Gate Charge	Q_{gs}		1	7	-	nC
	Q_{gd}	I _D =-10A	-	10	-	nC
Diode Forward Voltage	V_{FSD}	I _S =-12A, V _{GS} = 0V	-	-	-1.2	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

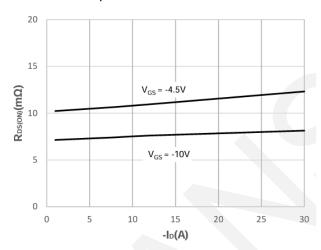


7. Typical electrical and thermal characteristics

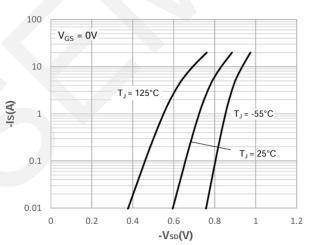




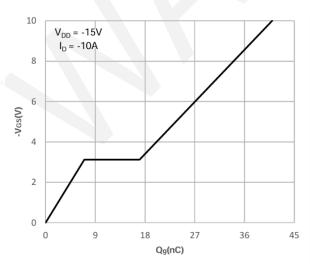
Output Characteristics



Typical Transfer Characteristics

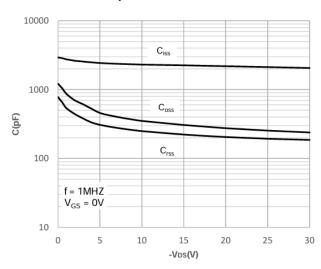


On-resistance vs. Drain Current



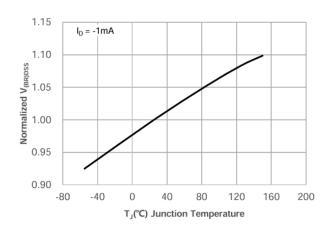
Gate Charge Characteristics

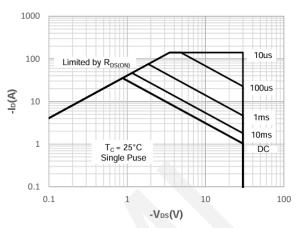
Body Diode Characteristics



Capacitance Characteristics



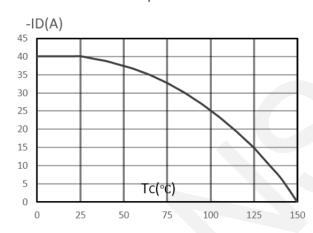




Maximum Safe Operating Area

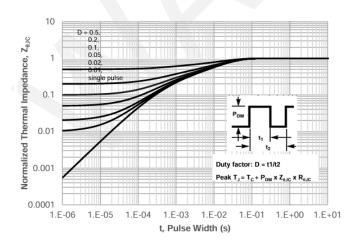
Normalized on Resistance vs.

Junction Temperature



Maximum Continuous Drain Current vs.

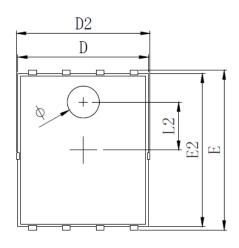
Case Temperature

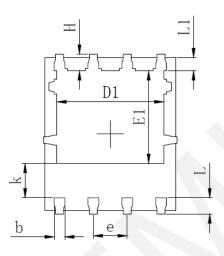


Maximum Effective Transient Thermal Impedance, Junction-to-Case



8.Package Dimensions





SYMBOL	MILLIMETER			
SIMDUL	MIN	Тур.	MAX	
A	0. 900	1.000	1. 100	
A1		0. 254 REF.		
A2		0~0. 05		
D	4. 824	4. 900	4. 976	
D1	3. 910	4. 010	4. 110	
D2	4. 924	5. 000	5. 076	
Е	5. 924	6. 000	6. 076	
E1	3. 375	3. 475	3. 575	
E2	5. 674	5. 750	5. 826	
b	0. 350	0. 400	0. 450	
е	1.270 TYP.			
L	0. 534	0. 610	0. 686	
L1	0. 424	0. 500	0. 576	
L2	1.800 REF.			
k	1. 190	1. 290	1. 390	
Н	0. 549	0. 625	0. 701	
θ	8°	10°	12°	
ф	1. 100	1. 200	1. 300	
d			0. 100	



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